



Title: METHOD AND APPARATUS FOR MEASUREMENT OF THIN FILMS
AND RESIDUES ON SEMICONDUCTOR SUBSTRATES

Inventor: Yehiel Gotkis

Docket No: LAM2P466 App. No: 10/810,209

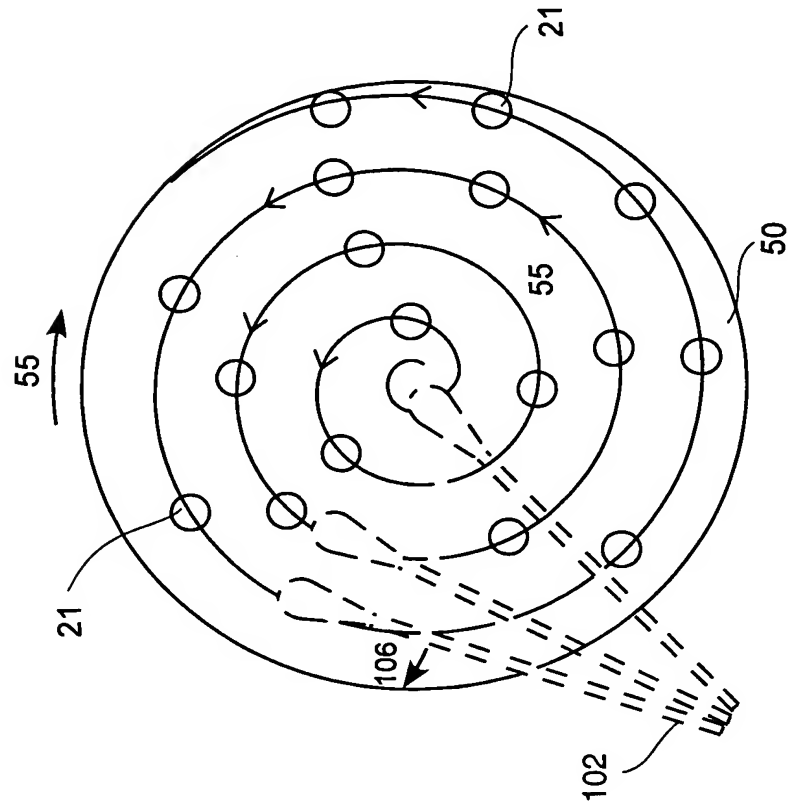


FIG. 4B

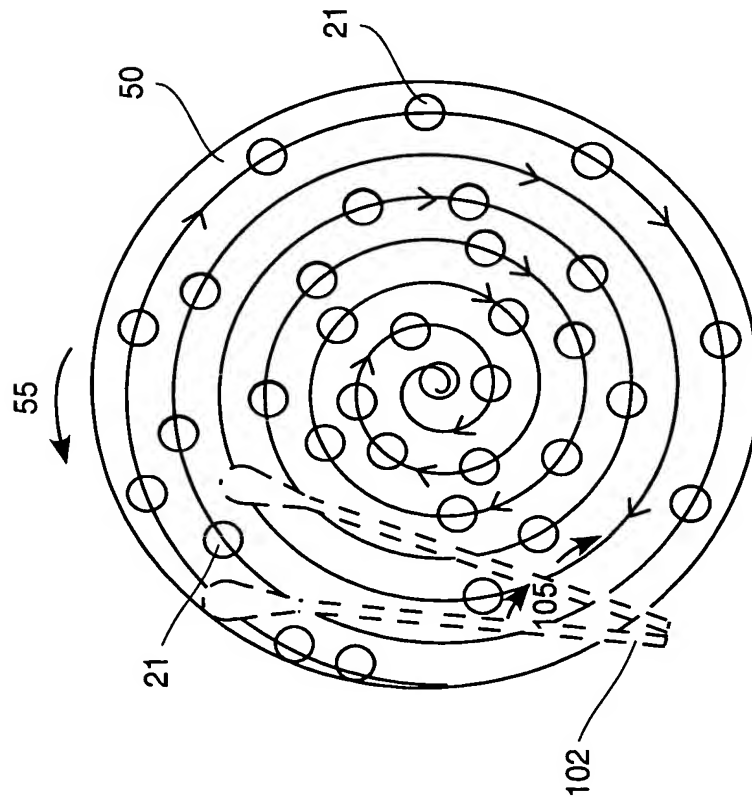


FIG. 4A